

4N0403D-VB TO220 Datasheet N-Channel 40-V (D-S) MOSFET

PRODUCT SUMMARY					
V _{DS}	40	V			
R _{DS(on)} V _{GS} = 10 V	2	mΩ			
I _D	180	Α			
Configuration	Single				

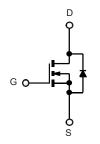
FEATURES

- Trench Power MOSFET
- 100 % R_g and UIS Tested



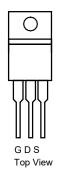
APPLICATIONS

- · Synchronous Rectification
- Power Supplies



N-Channel MOSFET

TO-220AB



Parameter	Symbol	Limit	Unit		
Drain-Source Voltage	V _{DS}	40	V		
Gate-Source Voltage	V _{GS}	± 20			
	T _C = 25 °C		180 ^{a, c}	A	
Continuous Drain Current (T _{.I} = 175 °C)	T _C = 70 °C	1-	150°		
Continuous Diain Current (1, - 175 C)	T _A = 25 °C	I _D	29 ^b		
	T _A = 70 °C		23 ^b		
Pulsed Drain Current	I _{DM}	350			
Avalanche Current Pulse	L = 0.1 mH	I _{AS}	80		
Single Pulse Avalanche Energy	L = 0.1 IIII	E _{AS}	320	mJ	
Ocation of Desire Binds Occurred	T _C = 25 °C	I-	110 ^{a, c}	A	
Continuous Source-Drain Diode Current	T _A = 25 °C	I _S	2.6 ^b		
Maximum Power Dissipation	T _C = 25 °C		312ª		
	T _C = 70 °C	В	200	w	
	T _A = 25 °C	P _D	3.13 ^b		
	T _A = 70 °C		2.0 ^b		
Operating Junction and Storage Temperature R	T _J , T _{stg}	- 55 to 150	°C		

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient ^b	Steady State	R_{thJA}	32	40	°C/W	
Maximum Junction-to-Case	Steady State	R _{thJC}	0.33	0.4	C/VV	

Notes:

- a. Based on T_C = 25 °C.
- b. Surface Mounted on 1" x 1" FR4 board.
- c. Calculated based on maximum junction temperature. Package limitation current is 110 A.

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Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static						
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	40			V
V _{DS} Temperature Coefficient	∆ V _{DS} /T _J	I _D = 250 μA		41		mV/°C
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	1 _D = 200 μΛ		- 8		
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2.0		4.0	V
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA
Zero Gate Voltage Drain Current	I _{DSS}	$V_{DS} = 40 \text{ V}, V_{GS} = 0 \text{ V}$			1	μA
Zero Gate Voltage Drain Gurrent		$V_{DS} = 40 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55 \text{ °C}$			10	μΑ
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	120			Α
Due in Course On Otata Basistanas	P	V _{GS} = 10 V, I _D = 30 A		2		mC
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = 4.5 \text{ V}, I_D = 20 \text{ A}$		15		mΩ
Forward Transconductance ^a	9 _{fs}	V _{DS} = 15 V, I _D = 30 A		180		S
Dynamic ^b						
Input Capacitance	C _{iss}			9000		pF
Output Capacitance	C _{oss}	$V_{DS} = 20 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		650		
Reverse Transfer Capacitance	C _{rss}			450		
Total Gate Charge	Qg			120		nC
Gate-Source Charge	Q _{gs}	$V_{DS} = 20 \text{ V}, V_{GS} = 10 \text{ V}, I_{D} = 20 \text{ A}$		30		
Gate-Drain Charge	Q _{gd}			16		1
Gate Resistance	R _g	f = 1 MHz		0.85	1.3	Ω
Turn-On Delay Time	t _{d(on)}			20	30	
Rise Time	t _r	$V_{DD} = 20 \text{ V}, R_{L} = 1.0 \Omega$		11	17	
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 20 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$		77	115	
Fall Time	t _f			10	15	
Turn-On Delay Time	t _{d(on)}			102	155	ns
Rise Time	t _r	$V_{DD} = 20 \text{ V}, R_L = 1.0 \Omega$		62	95	
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 20 \text{ A}, V_{GEN} = 4.5 \text{ V}, R_g = 1 \Omega$		180	270	
Fall Time	t _f			60	90	
Drain-Source Body Diode Characteristic	s					1
Continuous Source-Drain Diode Current	Is	T _C = 25 °C			110	
Pulse Diode Forward Current ^a	I _{SM}				200	A
Body Diode Voltage	V _{SD}	I _S = 20 A		0.8	1.2	V
Body Diode Reverse Recovery Time	t _{rr}			50	75	ns
Body Diode Reverse Recovery Charge	Q _{rr}	L = 20 A di/dt = 400 A/v. T = 25 °C		70	105	nC
Reverse Recovery Fall Time	t _a	$I_F = 20 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 ^{\circ}\text{C}$		30		
Reverse Recovery Rise Time	t _b			20		ns

Notes:

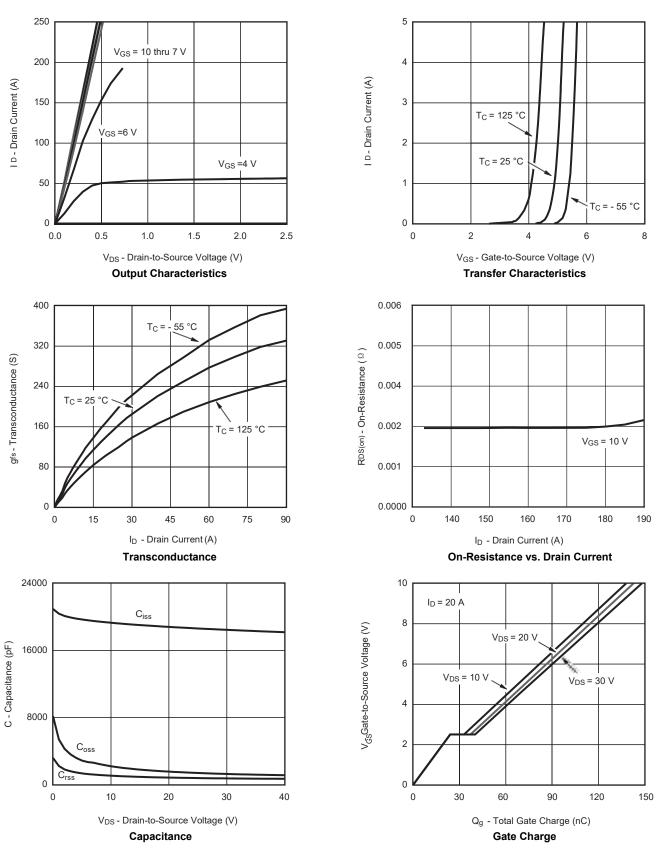
- a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

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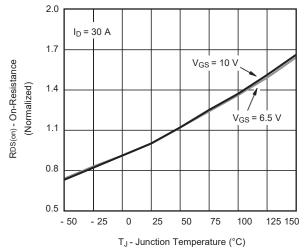


TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

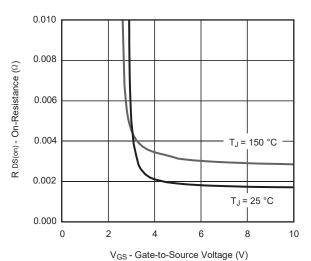




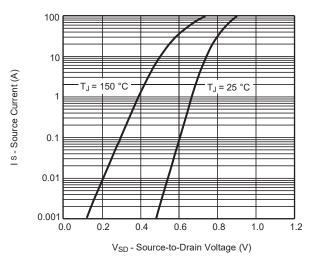
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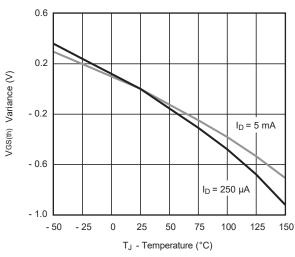
On-Resistance vs. Junction Temperature



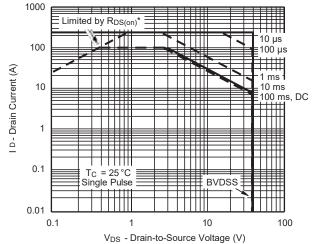
On-Resistance vs. Gate-to-Source Voltage



Forward Diode Voltage vs. Temperature



Threshold Voltage

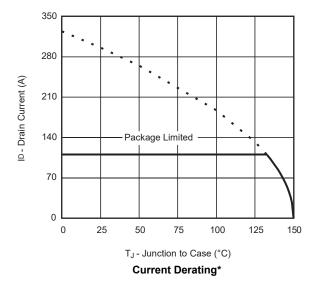


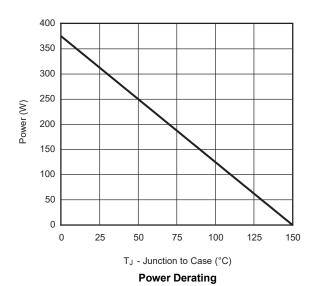
* V_{GS} > minimum V_{GS} at which R_{DS(on)} is specified

Safe Operating Area, Junction-to-Ambient

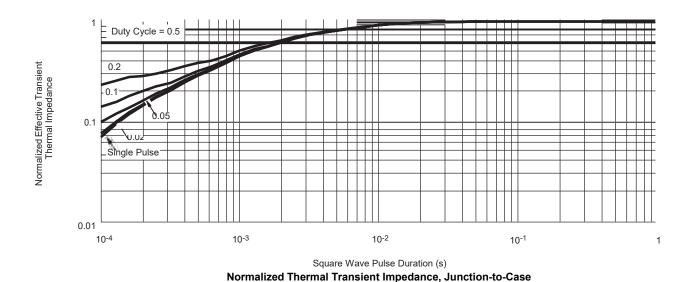


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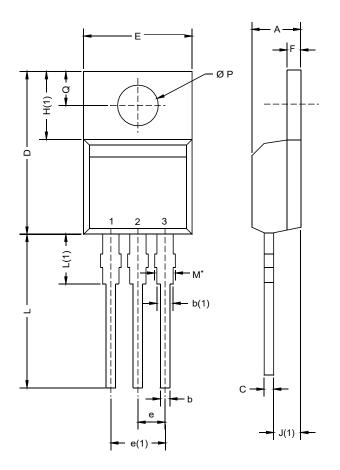


* The power dissipation P_D is based on $T_{J(max)}$ = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package





TO-220AB



	MILLIM	ETERS	INC	HES		
DIM.	MIN.	MAX.	MIN.	MAX.		
Α	4.25	4.65	0.167	0.183		
b	0.69	1.01	0.027	0.040		
b(1)	1.20	1.73	0.047	0.068		
С	0.36	0.61	0.014	0.024		
D	14.85	15.49	0.585	0.610		
Е	10.04	10.51	0.395	0.414		
е	2.41	2.67	0.095	0.105		
e(1)	4.88	5.28	0.192	0.208		
F	1.14	1.40	0.045	0.055		
H(1)	6.09	6.48	0.240	0.255		
J(1)	2.41	2.92	0.095	0.115		
L	13.35	14.02	0.526	0.552		
L(1)	3.32	3.82	0.131	0.150		
ØΡ	3.54	3.94	0.139	0.155		
Q	2.60	3.00	0.102	0.118		
ECN: X12-0208-Rev. N, 08-Oct-12 DWG: 5471						

Notes

 * M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM

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